

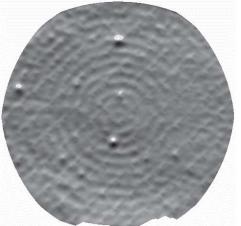
承湘科技股份有限公司

Wafer Surface Profiler

Fulfill all your needs with limited budget



非接觸式形貌量測
Non-contact measurement
高速擷取全域晶圓
600k point data in seconds
微米等級高解析度
Sub micro z resolution
3D彩色表面輪廓圖
3D彩色表面輪廓圖
3D colorful topography
晶圓膜層應力分析
Film stress analysis
晶圓形貌缺陷直讀
Surface protrusion inspection





#Bow, Warpage, Stress, Protrusion defect





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